

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/649,896	LEE, BYEONG-HOON
	<b>Examiner</b>	Art Unit
	George D. Spisich	3616

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner